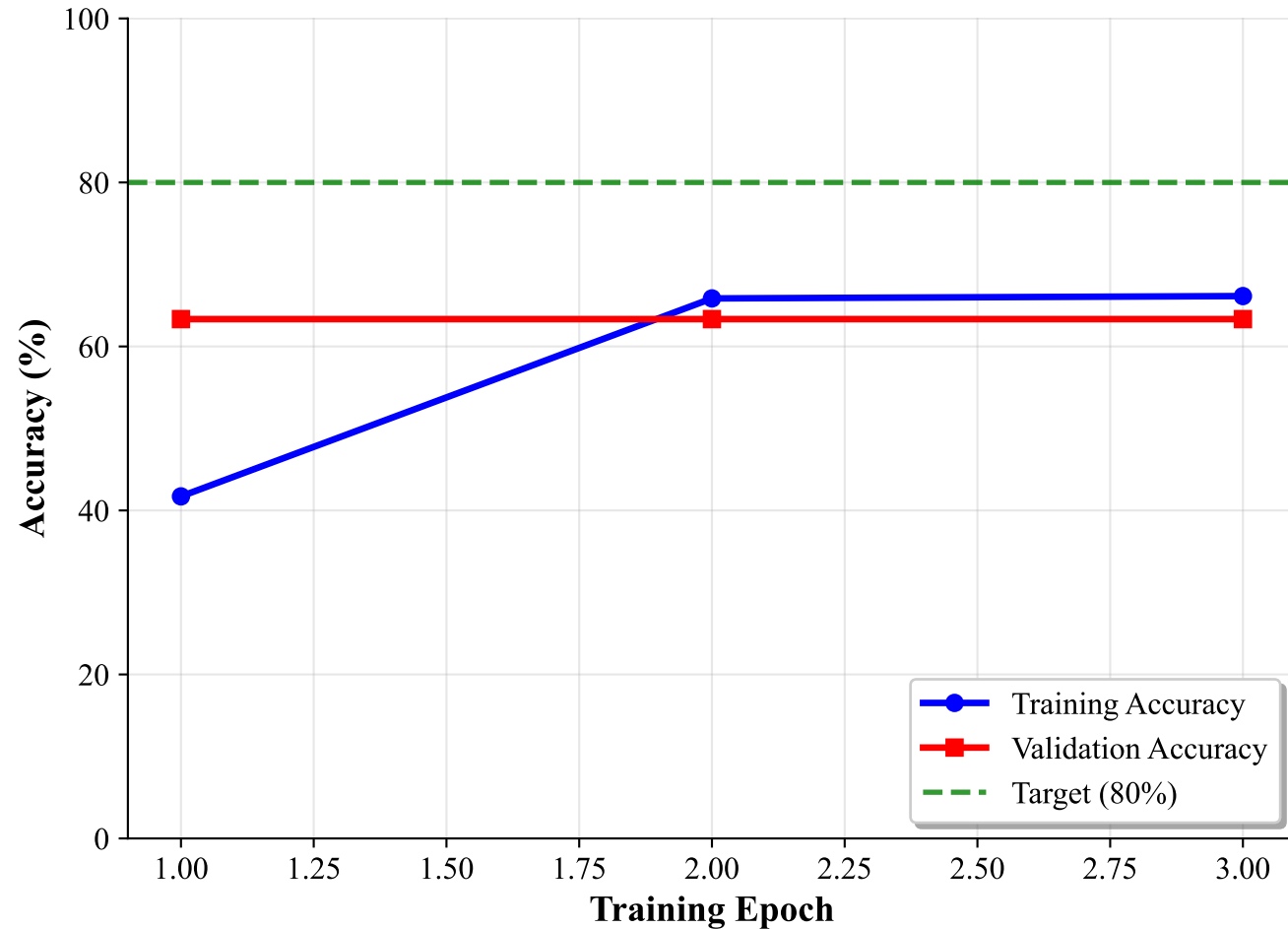


CNN Training Performance for Semiconductor Defect Classification

(a) Model Accuracy Progression



(b) Model Loss Progression

